

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/805,890	NALLAN ET AL.	
Examiner	Art Unit	Τ
Binh X. Tran	1765	

	SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Updated search	9/6/2006	ВТ	